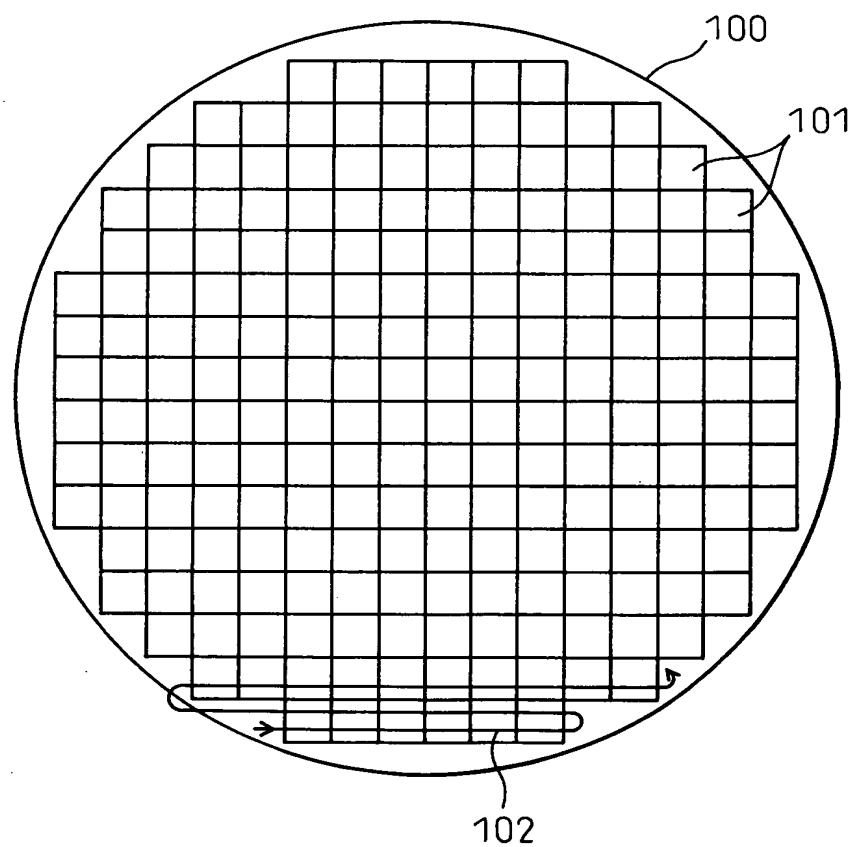


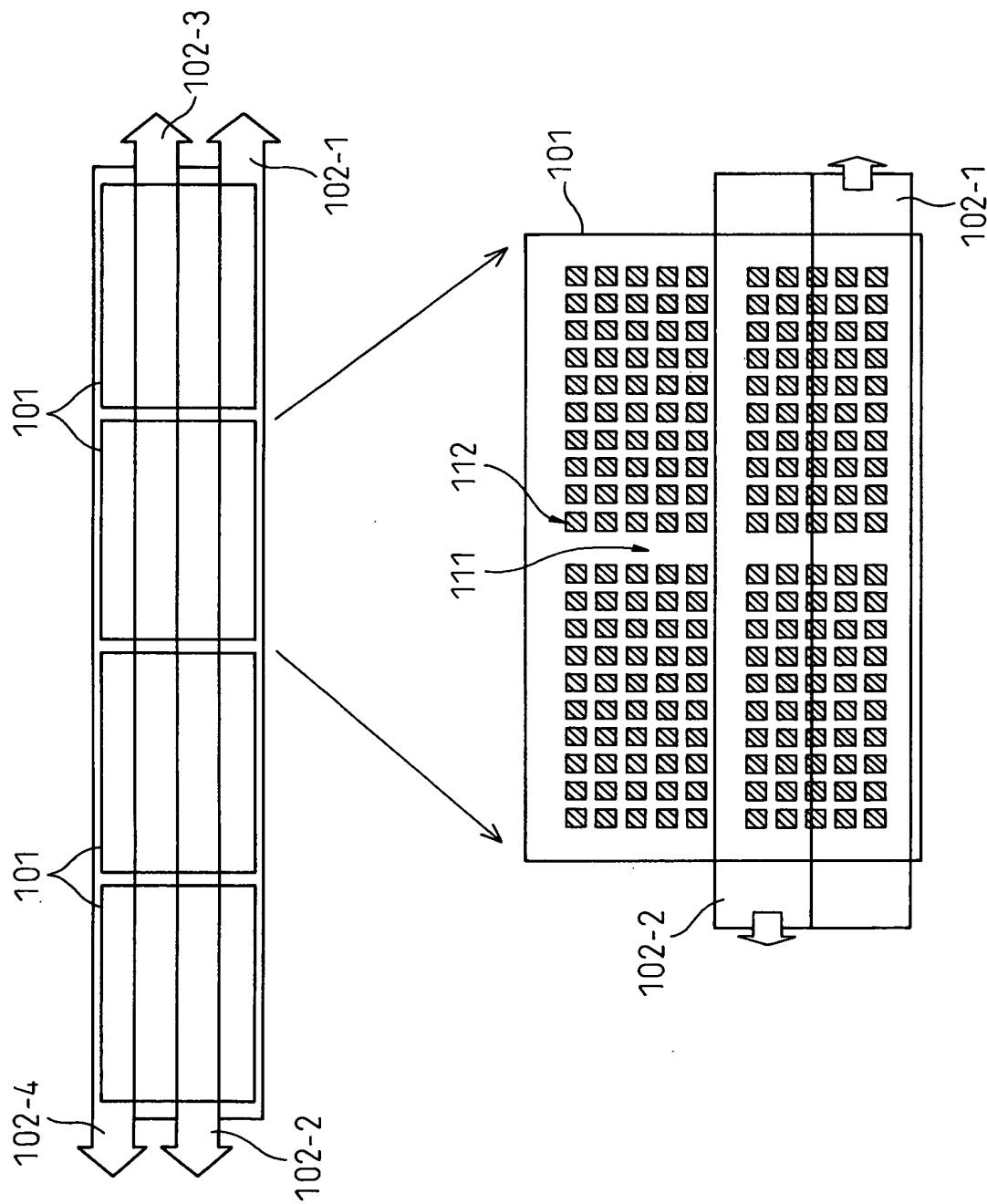
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FIG. 1



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FIG. 2



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FIG.3A

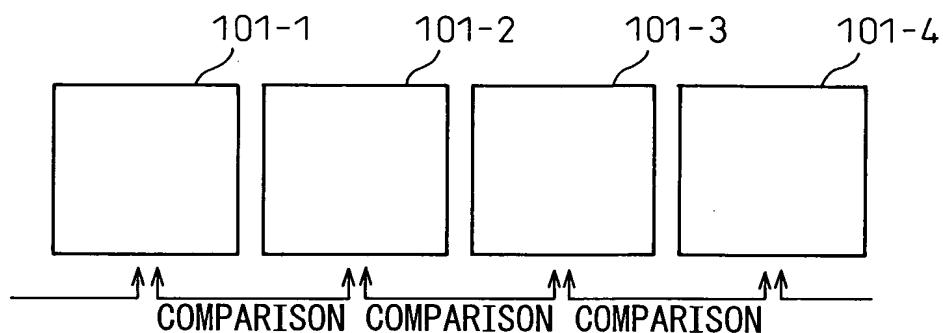


FIG.3B

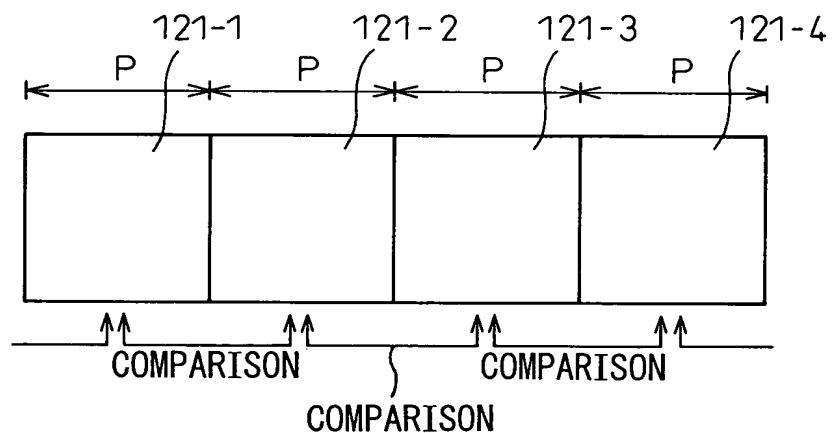


FIG.3C

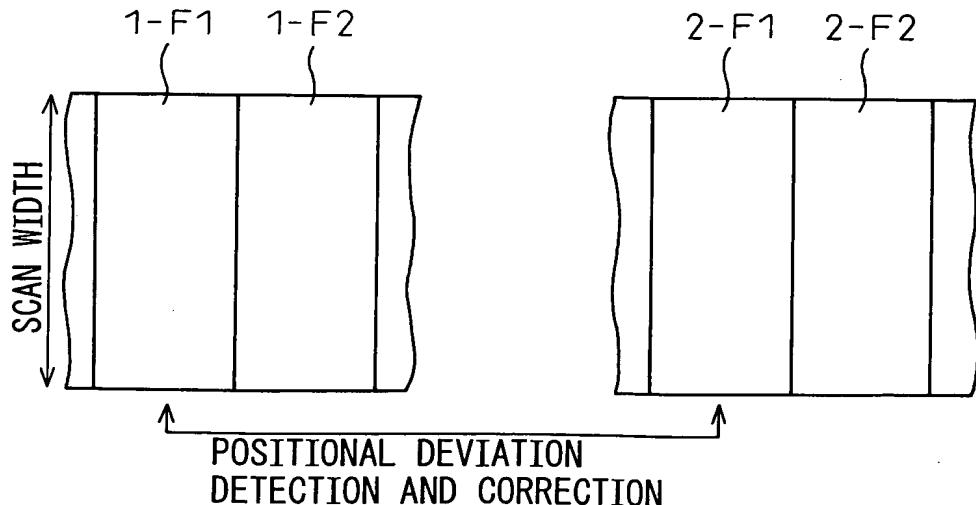
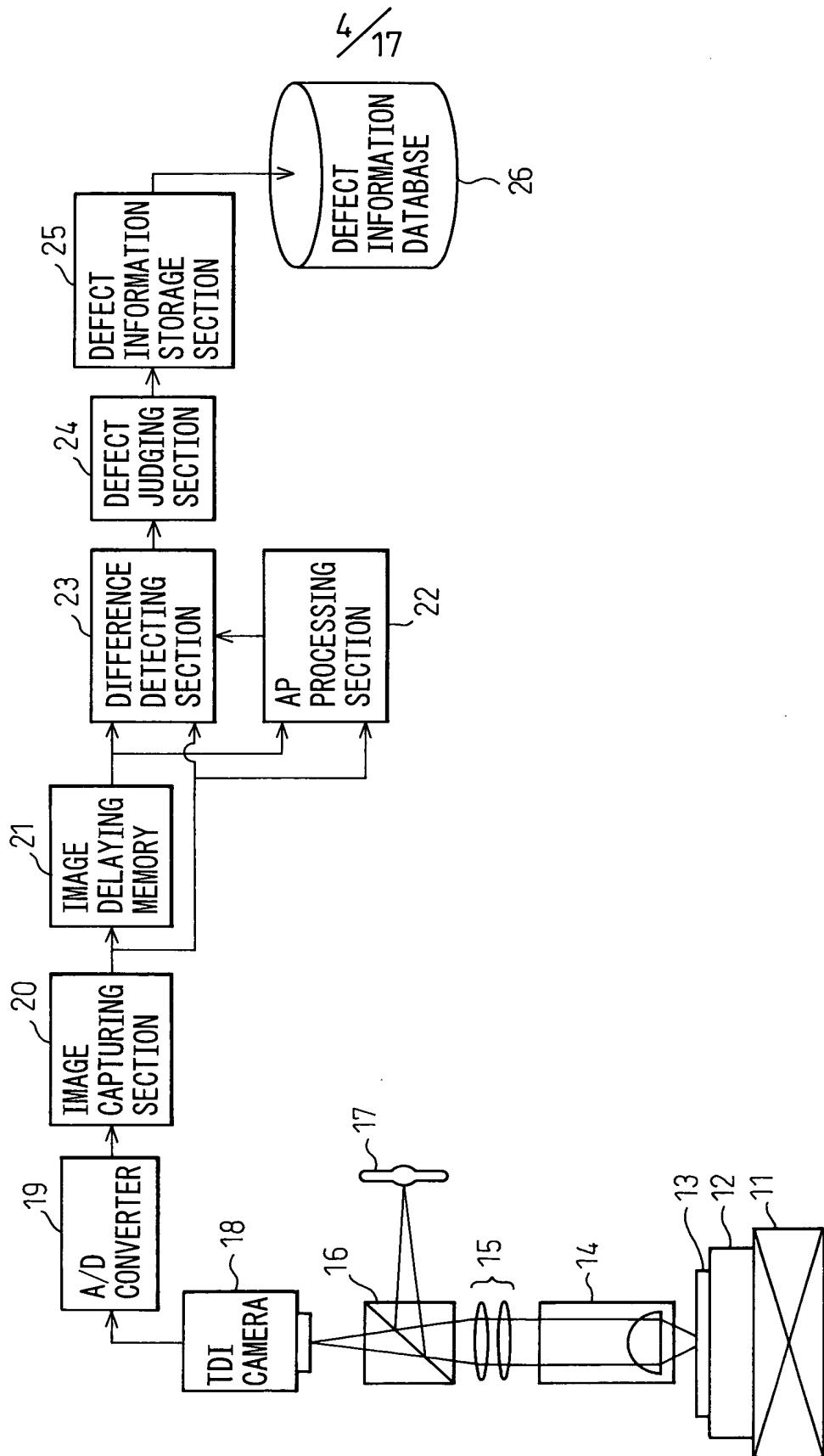
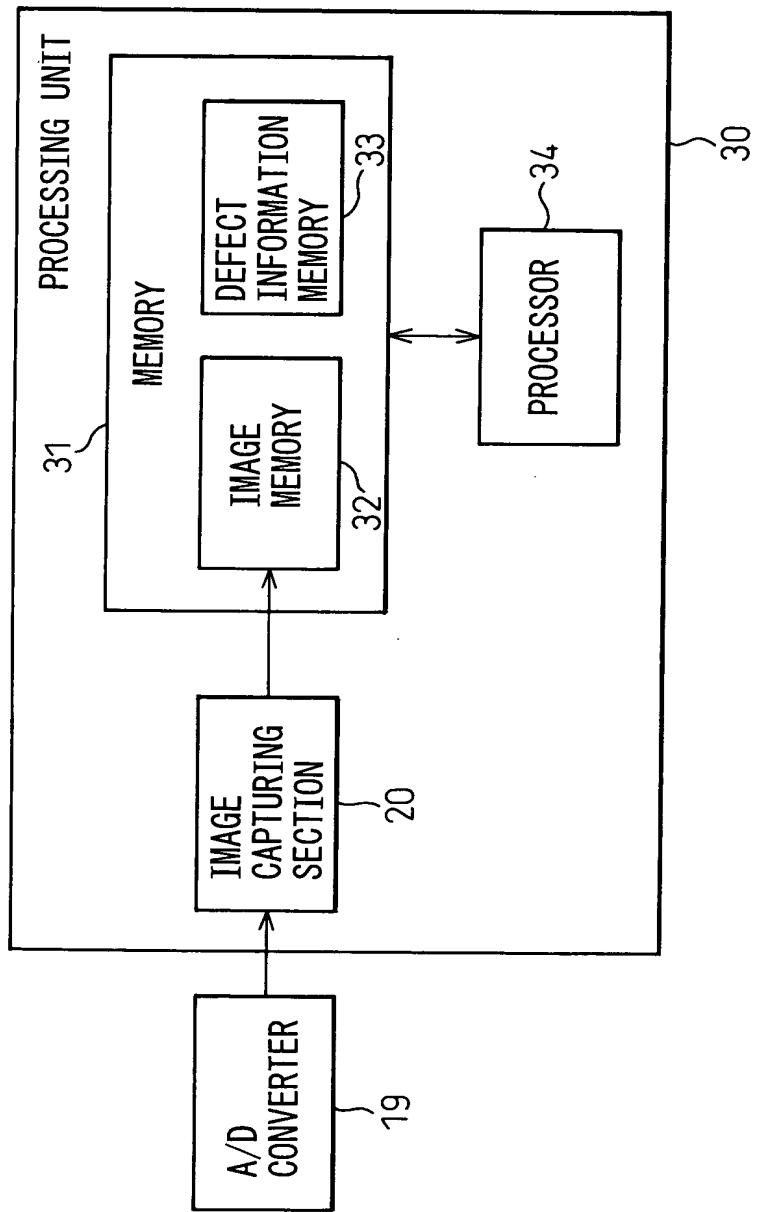


FIG. 4



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FIG. 5



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EIG.6A

DIE COMPARISON INSPECTION

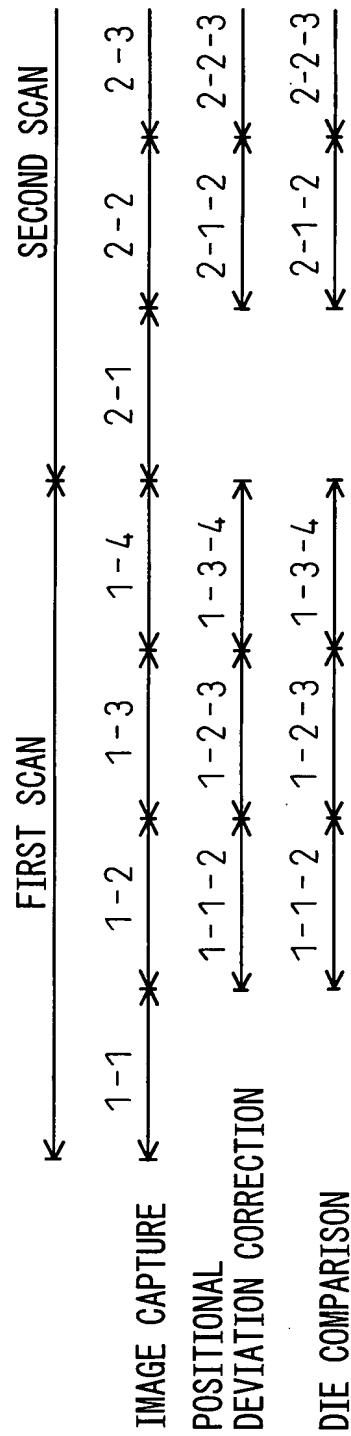
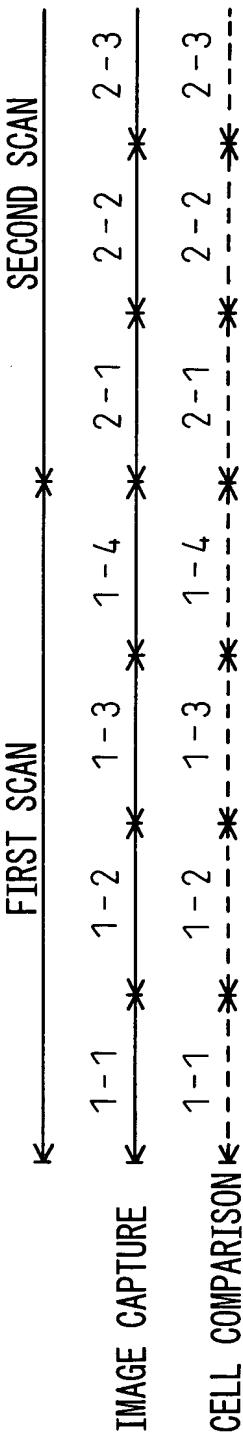


FIG. 6B

CELL COMPARISON INSPECTION



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FIG. 7

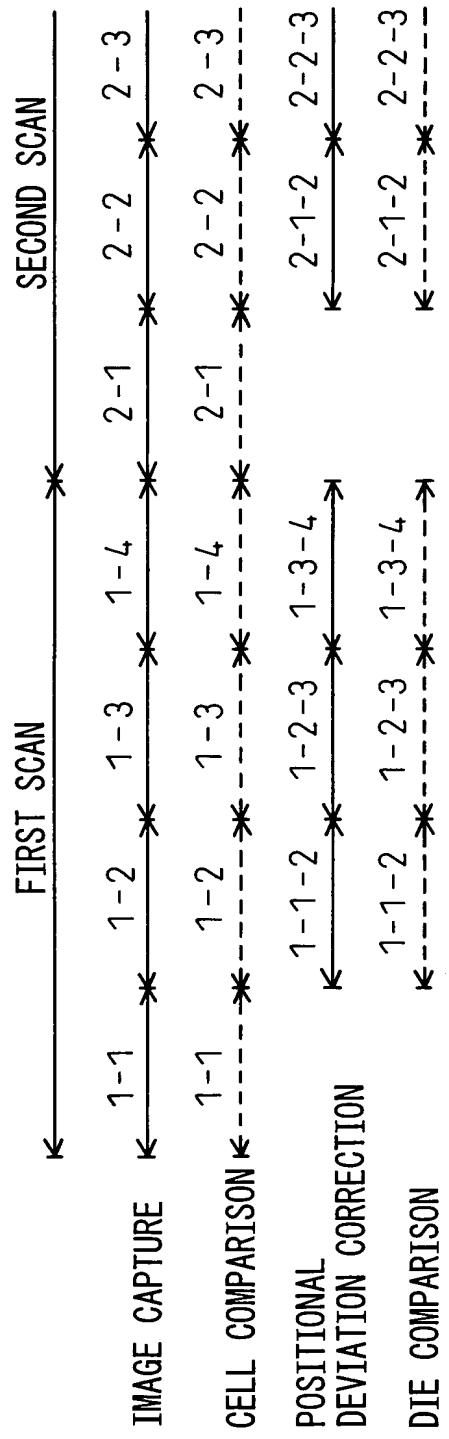
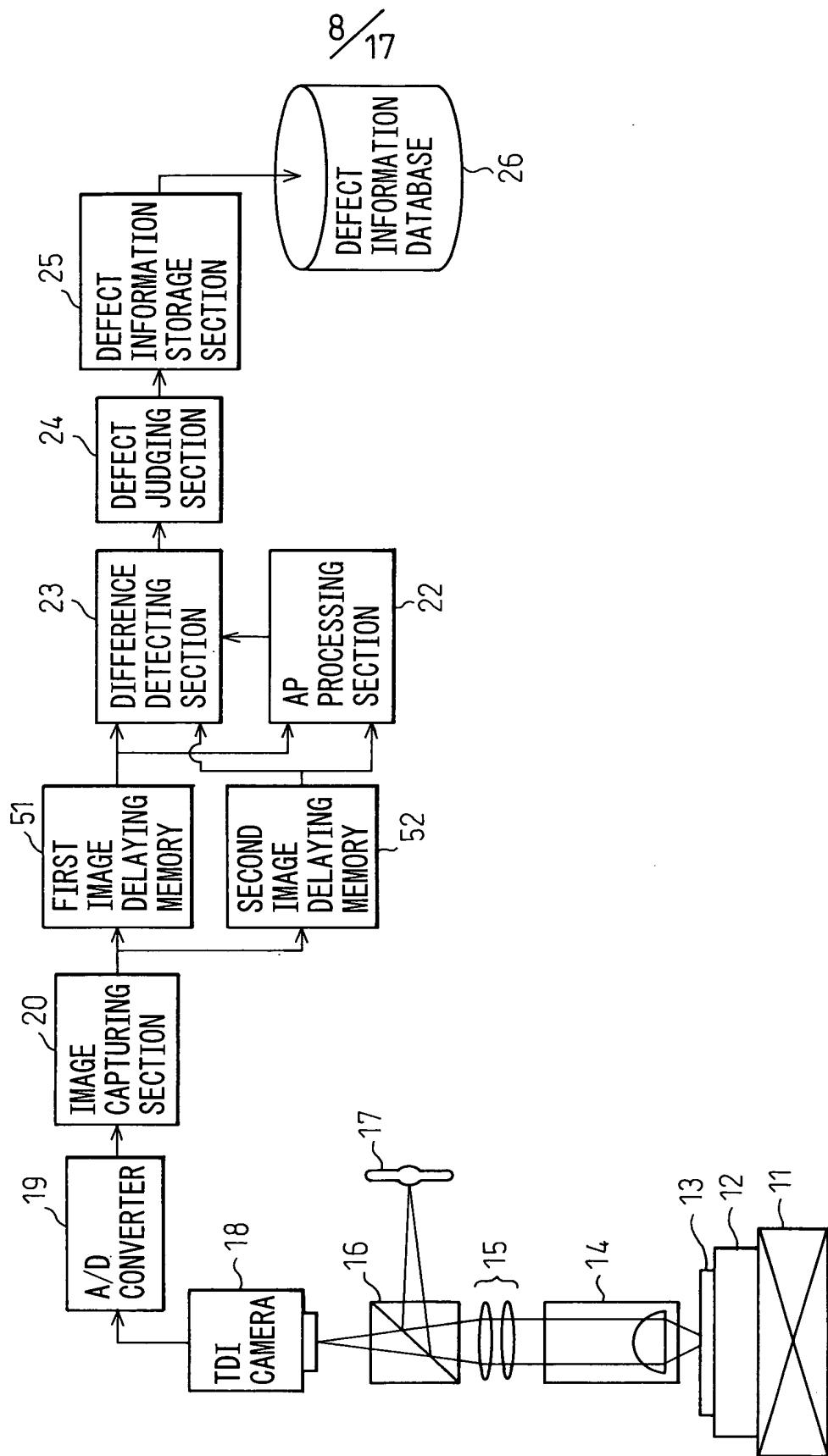
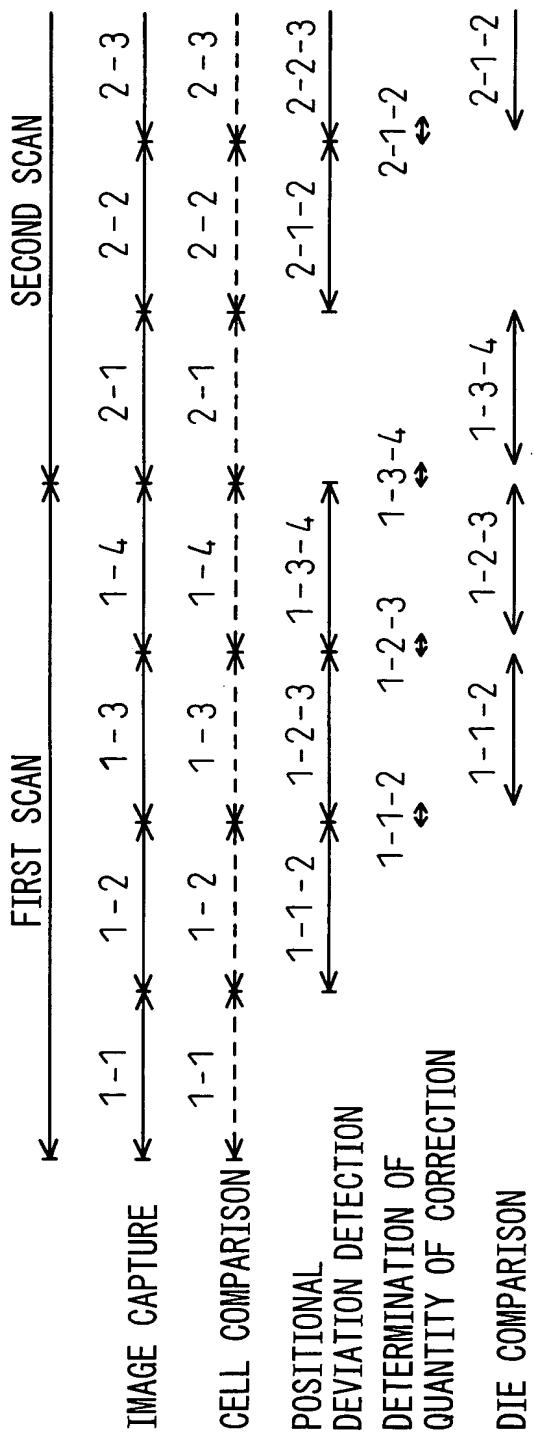


FIG. 8



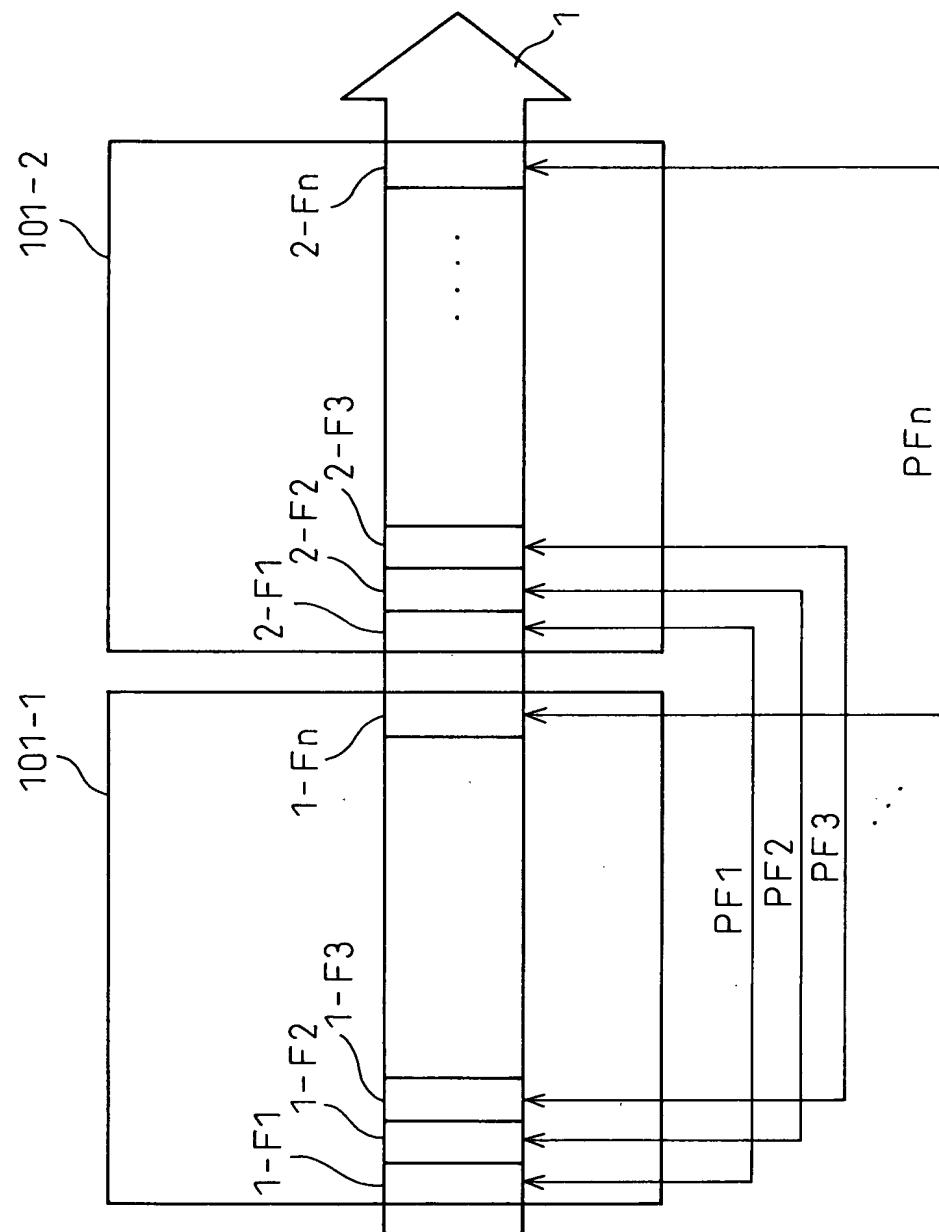
9
17

FIG. 9



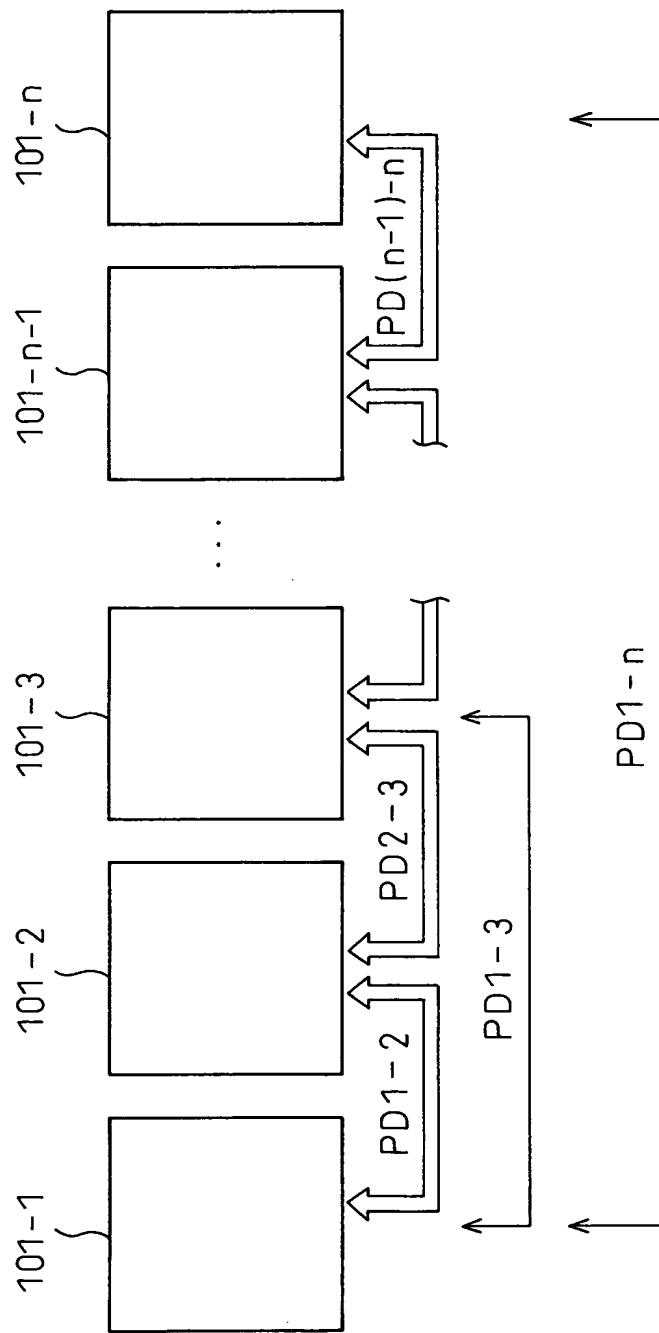
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FIG. 10



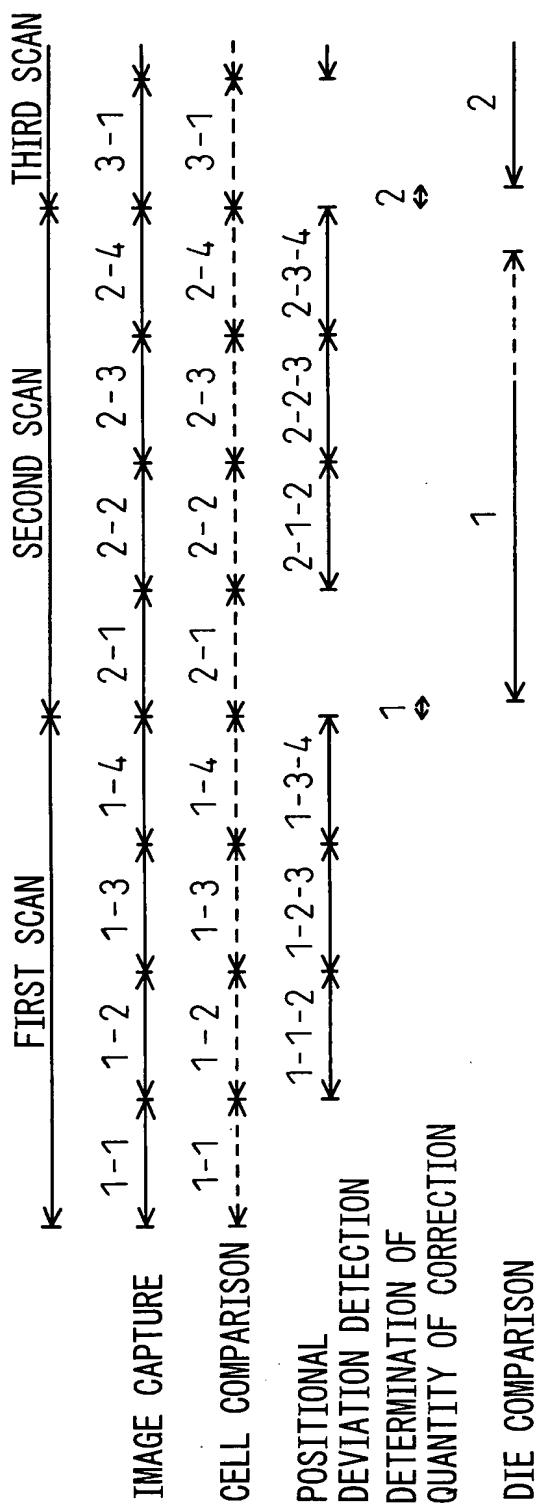
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FIG. 11



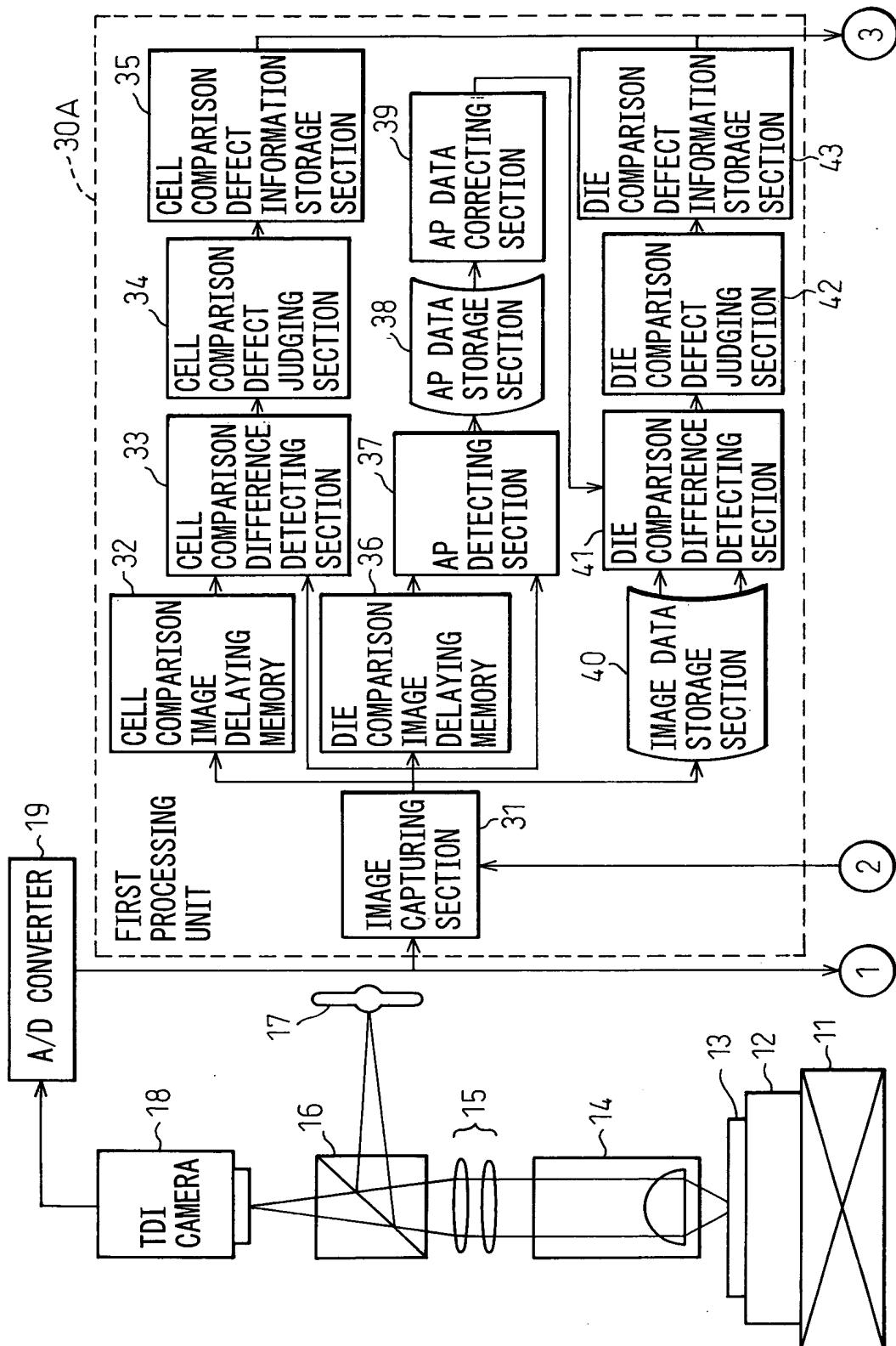
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FIG. 12



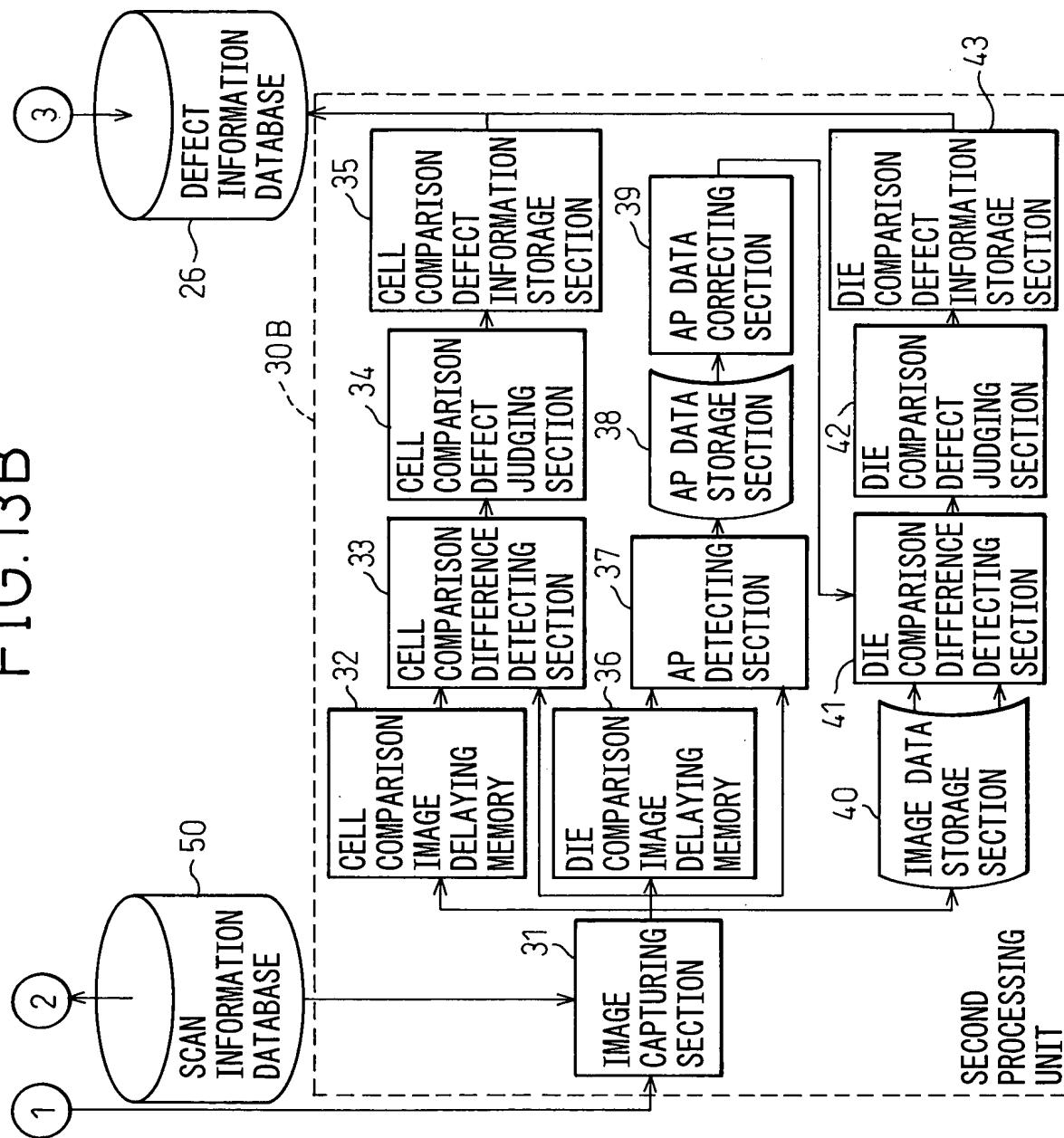
13
17

FIG. 13A



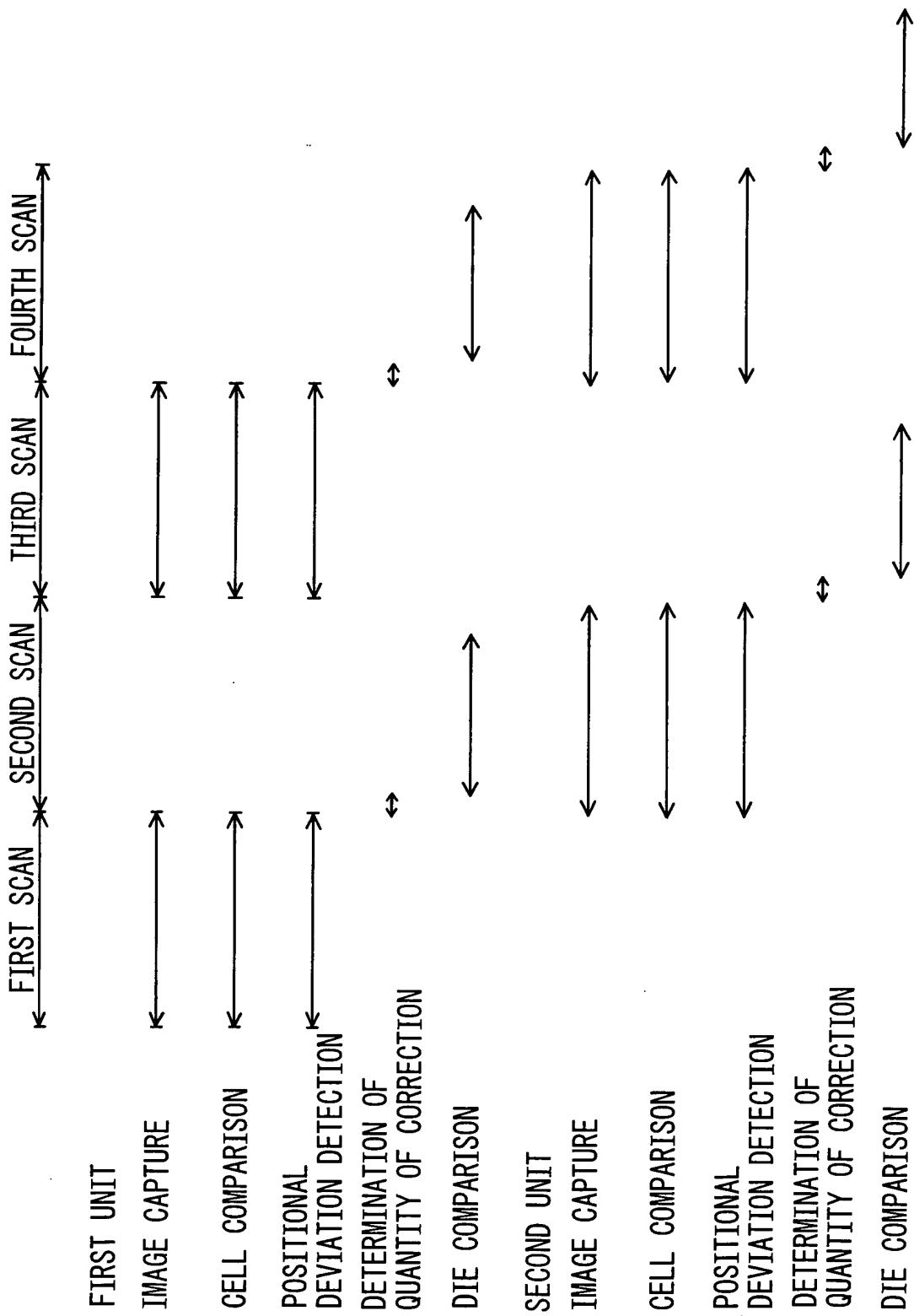
14
17

FIG. 13B



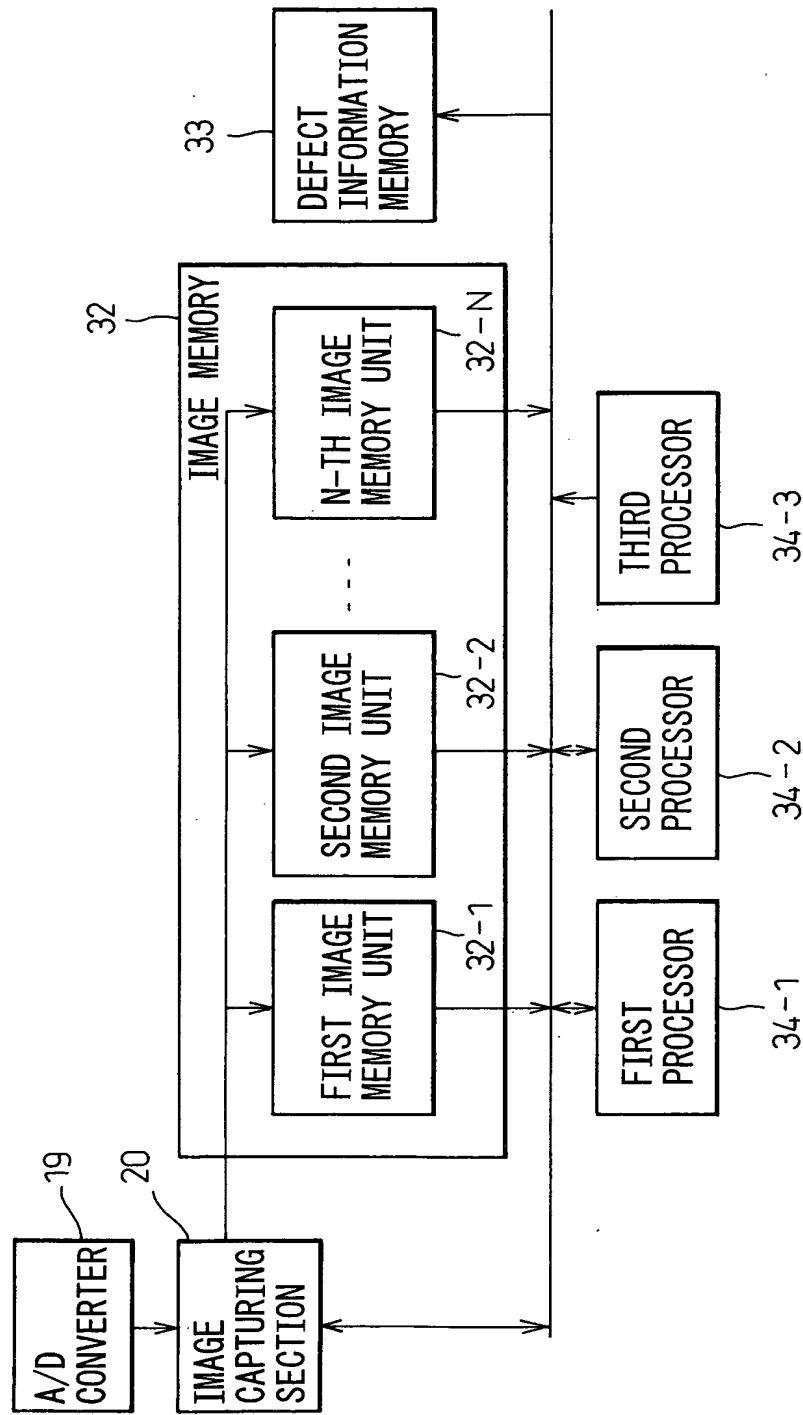
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FIG. 14



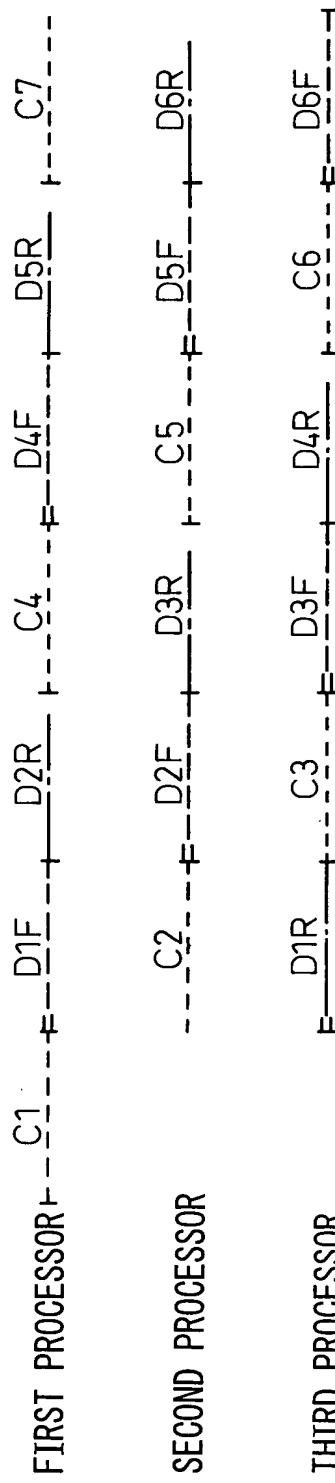
16
17

FIG.15



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FIG.16



CN — CELL COMPARISON AND POSITIONAL
DEVIATION DETECTION IN N-TH ROW

= DETERMINATION OF QUANTITY OF CORRECTION

DNF — DIE COMPARISON IN FIRST HALF IN N-TH ROW

DNR — DIE COMPARISON IN SECOND HALF IN N-TH ROW